Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

10/785,991

YANG, SWEEHAN J.H.
Art Unit

Examiner

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Steven J. Fulk

2891

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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